

XPS AND ION BEAM SCATTERING STUDIES OF LEACHING
IN
SIMULATED WASTE GLASS CONTAINING URANIUM

MASTER

by

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11	EXPS AND ION BEAM SCATTERING STUDIES OF LEACHING IN SIMULATED			11
12	WASTE GLASS CONTAINING URANIUM*			12
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25	ABSTRACT			25
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27	Glass samples (consisting of 2 mole % UO ₃ dissolved in a			27
28	number of complex borosilicate simulated waste glasses including			28
29	Battelle 76-68) were leached for varying times in distilled			29
30	water at 75°C. The glass surfaces were examined before and			30
31	after leaching using x-ray photoemission spectroscopy and back-			31
32	scattered ion beam profiling. Leached samples showed enhanced			32
33	surface layer concentrations of several elements including			33
34	uranium, titanium, zinc, iron and rare earths. An experiment			34
35	involving the leaching of two glasses in the same vessel showed			35
36	that the uranium surface enhancement is probably not due to			36
37	redeposition from solution.			37
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48	*Work supported by the U.S. Department of Energy.			48
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neutralization filament is used for preventing charge buildup on insulating samples. The system also included a sample fracture mechanism for exposing fresh surfaces under high vacuum ($\sim 10^{-10}$ torr) conditions allowing spectra to be taken which are characteristic of bulk unleached glasses.

Ion Beam Spectroscopy (IBS)

In order to develop models for the mechanisms involved in leaching, it is often important to be able to interpret XPS results in light of compositional variations over a broader depth range. One might then be able to judge whether the detailed bonding information inherent in the XPS technique was representative of the entire gel layer or just the immediate surface (perhaps a surface layer laid down by redeposition from solution).

Analysis by this technique is accomplished by bombarding the sample with alpha particles accelerated to a fixed energy (typically 2.9 MeV) and energy analyzing the backscattered particles. Most of the observed particles have undergone a single, large-angle, elastic scattering event. For a given detection angle, the particle retains a fixed fraction of its kinetic energy in this scattering depending only on the ratio, R, of the mass of the scattering nucleus to the mass of the alpha particle. This fraction, known as the kinematic factor is given by

$$K = \left[\frac{(R^2 - \sin^2 \theta)^{1/2} + \cos \theta}{R + 1} \right]^2$$

Most particles, however, are scattered from atoms at various distances beneath the surface. These particles have lost an additional amount of energy roughly proportional to the distance traveled through the sample. The spectra are readily interpretable as concentration profiles of the individual elements that have been shifted in energy and superposed. Typical distances analyzed are thousands of angstroms with resolutions of ~ 500 A.

Some of the features of Rutherford scattering spectrometry make its use in looking at actinides in complex glasses particularly attractive. In a complex glass such as 76-68, the large number of components means the elemental edges are rather close, making determination of individual profiles difficult at best. However, actinide atoms, being substantially heavier than the other elements present, have step edges above and separated from those of the other components making profiling rather straightforward. In addition, the cross section for scattering from a nucleus goes as Z^2 so that actinides are observable in lower concentrations than the lighter atoms.

1	EVEN	RUNNING HEAD	ODD	1
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3	SAMPLE PREPARATION			3
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5	The compositions of the simulated waste glasses used in			5
6	this study are given in Table 1. Samples of 7668, 3008, and 76-			6
7	101 were powdered, mixed with 2 mole % UO ₃ powder, and			7
8	remelted. Samples cut from the glass ingots were cut to appro-			8
9	priate shape, polished and cleaned with ethyl alcohol. Leaching			9
10	was performed in individual polypropylene containers at 75°C.			10
11	After drying, those samples which were to be examined by ion			11
12	backscattering were coated with ~200 Å of carbon to minimize			12
13	surface charging during ion bombardment. Unleached control sam-			13
14	ples were polished, cleaned, and carbon coated in a similar			14
15	manner. Rod shaped XPS samples were also prepared for fracture			15
16	under ultrahigh vacuum conditions.			16
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18	RESULTS	AUTHORS' AFFILIATION		18
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20	AND ADDRESS			20
21	Ion backscattering spectra of three different glass			21
22	compositions before and after leaching for one day in distilled			22
23	water at 75°C are shown in Figures 1-3. The figures represent			23
24	raw data in the form of counts as a function of backscattered			24
25	alpha particle energy. Because of the slow and smooth behavior			25
26	of the energy loss rate dE/dx as a function of energy, the			26
27	horizontal energy axis associated with a given elemental profile			27
28	may be thought of as an approximate depth scale.			28
29				29
30	Figure 1 shows data on the 76-101 + 2 mole % UO ₃ glass.			30
31	The profile edges of all of the elemental components of the			31
32	glass except boron (and any hydrogen left after leaching) are			32
33	apparent. Two features of the spectra are noteworthy. First,			33
34	there is very little change in the sodium profile after leach-			34
35	ing. This is in sharp contrast to a series of soda-lime-sil-			35
36	icate and soda-alumina-silicate glasses examined in an earlier			36
37	study. Second is a substantial enhancement of the titanium and			37
38	uranium concentrations near the glass surface. The uranium peak			38
39	is about 1.7 times as high as the level in the bulk glass and			39
40	appears to be no broader than the energy resolution of the			40
41	technique (equivalent to ~500 Å). The relative enhancement of			41
42	the titanium at the surface may be as great but the smaller			42
43	titanium signal is obscured by the statistical noise.			43
44				44
45	Figure 2 shows profiles of 3008 + 2 mole % UO ₃ glass.			45
46	Titanium and uranium show concentration enhanced surface layers			46
47	comparable to those in the 76-101 based glass. Zinc also shows			47
48	surface enhancement not readily apparent in the 76-101 based			48
49	glass. Iron and nickel present in the 3008 based glass do not			49
50	yield individual resolvable profiles but the composite Fe + Ni			50
51	profile does show surface enhancement.			51
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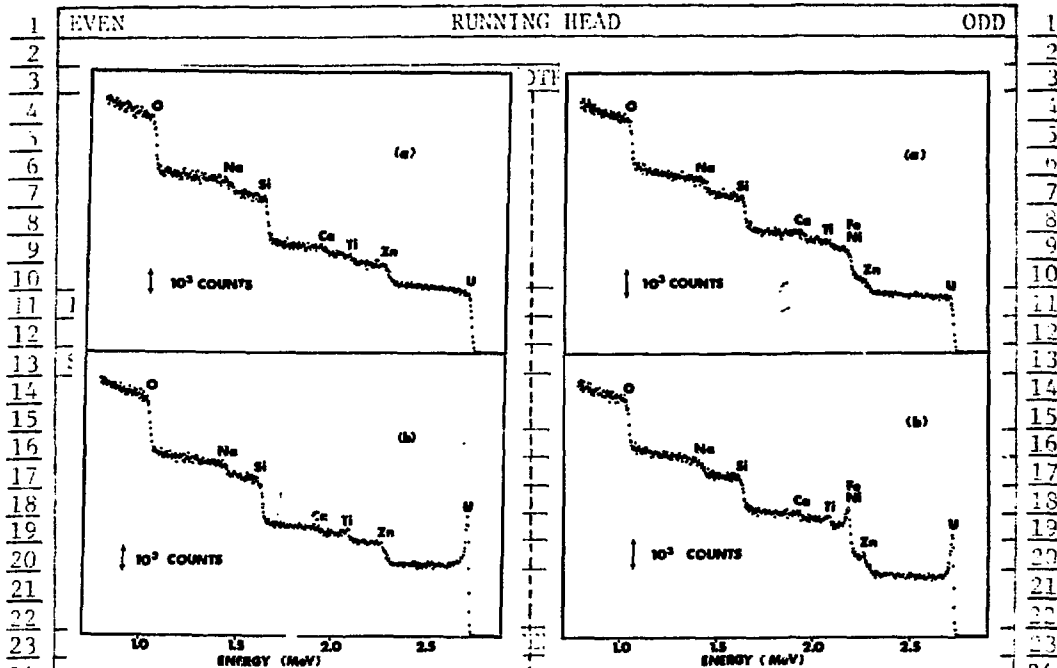


Fig 1. IBS profiles of 76-101 + 2% UO₃ (a) before (b) after leaching for 1 day at 75°C in distilled water.

Fig 2. IBS profiles of 3008 + 2% UO₃ (a) before (b) after leaching for 1 day at 75°C in distilled water.

Figure 3 shows profiles of 76-68 + 2 mole % UO₃ glass. The composition of this glass is quite complex and only the most prominent profile edges are noted. Many edges are weak and obscured but Fe + Ni enhancement is still clear. The rare earths are not individually distinguishable but their composite profile, designated Ce, Nd on the figures, show surface enhancement. The uranium enhancement in Figure 3 is similar to that in the other glass compositions.

Figure 4 shows 500 electron volt wide XPS spectra of 76-101 + 2% UO₃ glass for a freshly fractured surface (top) and after leaching in distilled water at 75°C for progressively longer periods. The intensity of a particular core line is proportional to the cross-section for photoemission from that core state times the concentration of that atomic species. The relative cross-sections can be determined by examination of the unleached sample which should be representative of the known bulk glass composition. For a given spectrum, concentrations can then be normalized to sum to 100%, thus determining the surface composition at different leach times. With this procedure, we find progressive enhancement in TiO₂ and UO₃ and, to a lesser extent, in ZnO as leach time increases (to 33%, 15%,

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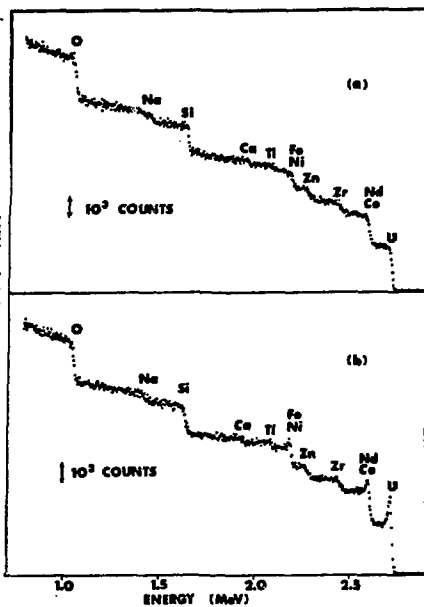


Fig 3. IBS profiles of 76-68 + 2% UO₃ (a) before (b) after leaching for 1 day at 75°C in distilled water.

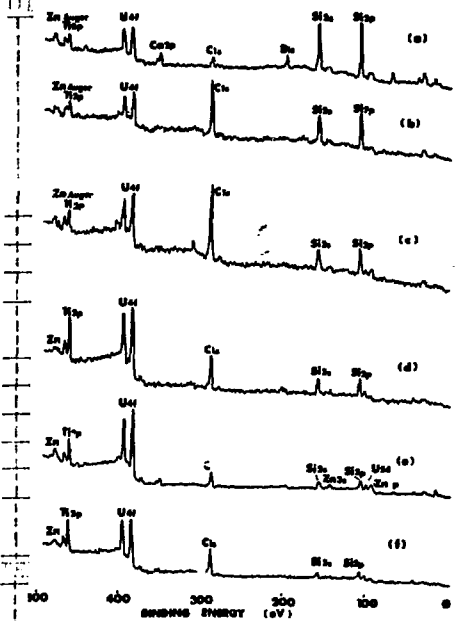


Fig 4. XPS spectra of 76-01 + 2% UO₃ (a) unleached, after leaching for (b) 1 hr (c) 3 hrs (d) 6 hrs (e) 1 day (f) 3 days at 75°C in distilled water.

and 18%, respectively, see Fig. 5). Necessarily, the SiO₂ concentration is reduced. In the earliest stages of leaching, there is an initial increase in SiO₂ presumably due to the even more rapid loss of Na and B.

The enhancement of U and Ti as seen by XPS is substantially greater than the peak enhancement as seen on the IBS profiles. The reason for this is that the IBS profile can only give the enhancement factor averaged over its depth resolution. The surface peaks in the true U and Ti profiles must be considerably narrower than the IBS profiles show and at least as high as the enhancement observed in the XPS spectra. Information from both techniques is valuable in studying the evolution of the leaching process; IBS to give the integrated excess U or Ti in the entire surface region, and XPS to give detailed compositional and chemical information about the 20-30 Å layer right, at the glass-solution interface.

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3	Surface enhancement could result from selective leaching		
4	or by redeposition from solution. An experiment was performed		
5	to determine which mechanism was responsible for the uranium		
6	enhancement in the 76-101 based glass. Two glass samples (one		
7	plain 76-101 and one containing UO ₃) were placed in the same		
8	polypropylene container with ~2 ounces of distilled water and		
9	leached at 75°C for 24 hours as before. Gentle agitation was		
10	provided every few hours. If the uranium was being dissolved		
11	and redeposited it should be detectable on both glass		
12	surfaces. XPS examination of the plain 76-101 glass did not		
13	reveal any uranium present indicating that the observed		
14	enhancement was due to selective leaching of other components		
15	and not redeposition from solution.		
16	AUTHORS' NAMES		
17	Figure 6a and b show XPS spectra of 76-68 + 2% UO ₃ glass		
18	fractured in vacuum and leached for one day in distilled water		
19	at 75°C respectively. As the number of components increases,		
20	identification of many features in the spectra becomes more		
21	difficult. The relative surface concentrations of U, Si, Ti and		
22	Zn seem to be similar to the 76-101 based glass. Zr shows		
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47	Fig 5. 76-101 + 2% UO ₃ glass		
48	surface composition vs.		
49	leaching time at 75°C in		
50	distilled water as deter-		
51	mined from data in Fig. 4.		
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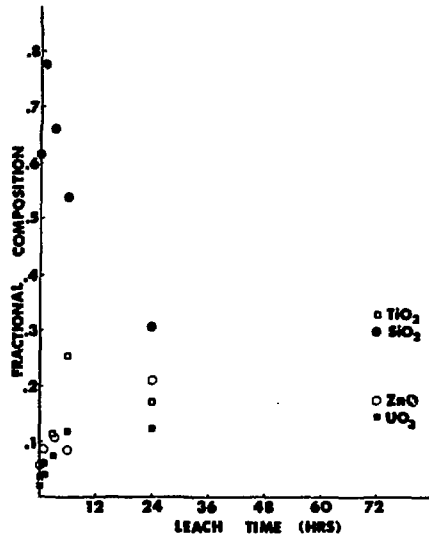


Fig 5. 76-101 + 2% UO₃ glass surface composition vs. leaching time at 75°C in distilled water as determined from data in Fig. 4.

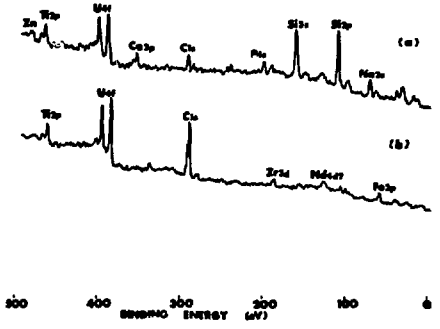


Fig 6. XPS spectra of 76-68 + 2% UO₃ (a) unleached; (b) leached for 1 day at 75°C in distilled water.

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3	substantial surface enhancement (rather ambiguous in the IBS			3
4	profile). The Fe + Ni profile peak in the IBS spectrum would			4
5	appear to be predominantly Fe from the XPS data.			5
6				6
7	CONCLUSIONS			7
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9	The surface composition of 76-101, 3008, and 76-68 simu-			9
10	lated waste glasses containing UO ₂ have been examined before and			10
11	after leaching. Distilled water leaching in all of the glasses			11
12	was characterized by the removal of Si, B, and Na from the sur-			12
13	face region leaving a surface enhanced in Ti, Zn, Fe, the			13
14	rare earths, and U.			14
15				15
16	The overall similarity in the behavior of the elements			16
17	common to 76-101 and 76-68, especially uranium, is encour-			17
18	aging. XPS valence state identification in other actinides may			18
19	rely on the analysis of weak satellite lines which might easily			19
20	be obscured in the crowded spectra of 76-68. It would be much			20
21	easier to study actinide behavior in the similar but simpler 76-			21
22	101 glass.			22
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24	ACKNOWLEDGEMENTS			24
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31	Energy. The authors wish to thank A. W. Mitchell for his able			31
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